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Electron Microscopy School, Belgrade, April 2011

High-Angle Annular Dark-Field Scanning Transmission Electron Microscopy (HAADF-STEM)

# Lecture key points:

- Why are we doing HAADF-STEM?
- The reciprocity theorem of elastic electron scattering
- The origin of thermal diffuse scattering
- The electron probe
- The ronchigram
- Quantitative HAADF-STEM imaging
  - Image simulations
  - Quantitative interpretation of atomically-resolved HAADF-STEM images

### TEM microscope in the begining...





- Two basic operation modes in transmission electron microscopy (TEM):
- using stationary electron beam (conventional TEM mode)
- using scanning electron probe (STEM mode)



Combined atomically-resolved structural, compositional and chemical information:

- STEM: Scanning Transmission Electron Microscope
- HAADF: High-Angle Annular Dark-Field detektor



HAADF-STEM of functional materials:

strong compositional sensitivity

Why are we doing HAADF-STEM?





V. Radmilović (2011)

### HAADF-STEM of nanoparticles:

- Cu-Ni-Pt nanoparticle in carbon-based matrix
- Ru-O nanoparticles in TiO<sub>2</sub> based matrix



Hollow nanospheres

# Why are we doing HAADF-STEM?





Combining Bright-Field (BF) and HAADF-STEM imaging:

compositionally complex nanotube





Combining Bright-Field (BF) and HAADF-STEM imaging:
Pd on perovskite substrate

## Why are we doing HAADF-STEM?

### Small region of polycrystalline BaTiO<sub>3</sub> tubes



Images were taken at SuperSTEM (Daresbury)

Combining Bright-Field (BF) and HAADF-STEM imaging:

- Atomic-scale sensitivity
- Strong chemical and structural sensitivity

Why are we doing HAADF-STEM?

### Small region of polycrystalline BaTiO<sub>3</sub> tubes



Images were taken at SuperSTEM (Daresbury)

Combining Bright-Field (BF) and HAADF-STEM imaging:

 The interpretation of HAADF-STEM images is more straight forward than BF-STEM













The origin of thermal diffuse scattering







- Intensity of high-angle scattered electrons is related with projected average atomic number, Z
- Proper setting of the detector will collect only high-angle scattered electrons, thus increase the Z-contrast





The probe functions at optimum convergence angle



# How to define best probe for imaging?





Oak ridge nationa lab

# The ronchigram

How to define best probe for imaging? Make use of a ronchigram



Experimental image taken on JEM-2010F (15.4.2010)









HAADF-STEM imaging at high spatial resolution:

- Z-contrast
- Atomic-scale combined compositional and structural sensitivity



Z-contrast

Atomic-scale combined compositional and structural sensitivity



Need for qunatitative interpretation of atomicaly resolved HAADF-STEM images

HAADF-STEM image simulatons

## HAADF-STEM image simulations



### HAADF-STEM image simulations



#### Incomplete list of HAADF-STEM image simulations softwares:

- C. Koch: QSTEM (http://www.christophtkoch.com/stem/index.html)
- E.J. Kirkland: Advanced Computing in Electron Microscopy
- P. Galindo: HAADF-STEM image simulations on large scale nanostructures
- V. Grillo: STEM\_CELL (http://tem.s3.infm.it/software)
- <u>http://www.hremresearch.com/</u> (commercial software)



Image matching alghoritm: Cross-correlation data cube



Quantitative HAADF-STEM

### SrTiO<sub>3</sub> + 10 mol.%SrO



## Quantitative HAADF-STEM

